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Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references at the end of each chapters and index.
Nota di contenuto	Preface -- Introduction to TEM, HRTEM and aberration corrected microscopy -- Electron diffraction and crystal orientation phase mapping under scanning transmission electron microscopy -- Advanced Electron Microscopy in the Study of Multi metallic Nanoparticles -- Zeolites and Ordered Mesoporous materials under the electron microscope -- Local TEM spectroscopic studies on carbon- and boron nitride-based nanomaterials -- 3D-nanometric analyses via

electron tomography: application to nanomaterials -- In situ TEM of carbon nanotubes -- Physical characterization of nanomaterials in dispersion by transmission electron microscopy in a regulatory framework.

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Sommario/riassunto

This book highlights the current understanding of materials in the context of new and continuously emerging techniques in the field of electron microscopy. The authors present applications of electron microscopic techniques in characterizing various well-known & new nanomaterials. The applications described include both inorganic nanomaterials as well as organic nanomaterials.

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